



Description

The HXYG45N10P use advanced SGT MOSFET technology to provide low $R_{DS(ON)}$, low gate charge, fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness.

General Features

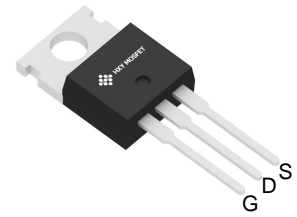
$V_{DS} = 100V, I_D = 45A$

$R_{DS(ON)} < 16m\Omega @ V_{GS} = 10V$

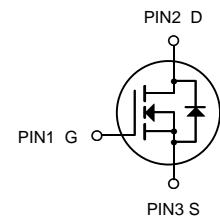
Application

Power switch

DC/DC converters



TO-220



N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
HXYG45N10P	TO-220	45N10 XXXX	50

Absolute Maximum Ratings ($T_c = 25^\circ C$ unless otherwise noted)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		100	V
V_{GSS}	Gate-Source Voltage		± 20	V
I_D	Continuous Drain Current		45	A
I_{DM}	Pulsed Drain Current ^{note1}		135	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		18	mJ
P_D	Power Dissipation	$T_C = 25^\circ C$	95	W
$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.45	$^\circ C/W$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ C$



Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV _{DSS}	V _{GS} =0 V, I _D =250uA	100	---	---	V
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250uA	1.0	---	3.0	V
Drain-source leakage current	I _{DSS}	V _{DS} =100V, V _{GS} =0V, T _J = 25°C	---	---	1	μA
		V _{DS} =80V, V _{GS} =0V, T _J = 125°C	---	---	10	μA
Gate leakage current, Forward	I _{GSSF}	V _{GS} =20 V, V _{DS} =0 V	---	---	100	nA
Gate leakage current, Reverse	I _{GSSR}	V _{GS} =-20 V, V _{DS} =0 V	---	---	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =16 A	---	13.9	16	mΩ
		V _{GS} =4.5 V, I _D =8 A	---	18.1	23	mΩ
Forward transconductance	g _{fs}	V _{DS} =10V , I _D =10A	---	60	---	S
Dynamic characteristics						
Input capacitance	C _{iss}	V _{DS} = 50 V, V _{GS} = 0 V, F = 1MHz	---	916	---	pF
Output capacitance	C _{oss}		---	484	---	
Reverse transfer capacitance	C _{rss}		---	36	---	
Turn-on delay time	t _{d(on)}	V _{DD} = 50V,V _{GS} =10V, I _D = 25A	---	17.3	---	ns
Rise time	t _r		---	4.3	---	
Turn-off delay time	t _{d(off)}		---	30.5	---	
Fall time	t _f		---	5.7	---	
Gate resistance	R _g	V _{GS} =0V, V _{DS} =0V, F=1MHz	---	1.5	---	Ω
Gate charge characteristics						
Gate to source charge	Q _{gs}	V _{DS} =50 V, I _D =25A, V _{GS} = 10 V	---	15.6	---	nC
Gate to drain charge	Q _{gd}		---	2.8	---	
Gate charge tota	Q _g		---	3.2	---	
Drain-Source diode characteristics and Maximum Ratings						
Diode Forward Voltage ⁴⁾	V _{SD}	V _{GS} =0V, I _S =50A, T _J =25°C	---	---	1.3	V
Reverse Recovery Time	t _{rr}	I _S =20A, di/dt=60A/us, T _J =25°C	---	52	---	ns
Reverse Recovery Charge	Q _{rr}		---	61.6	---	nC

Notes:

- 1: The maximum junction current rating is package limited.
- 2: Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3: $V_{DD}=50\text{V}, V_{GS}=10\text{V}, L=0.5\text{mH}, I_{AS}=31\text{A}, R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$.
- 4: Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.



Typical Performance Characteristics

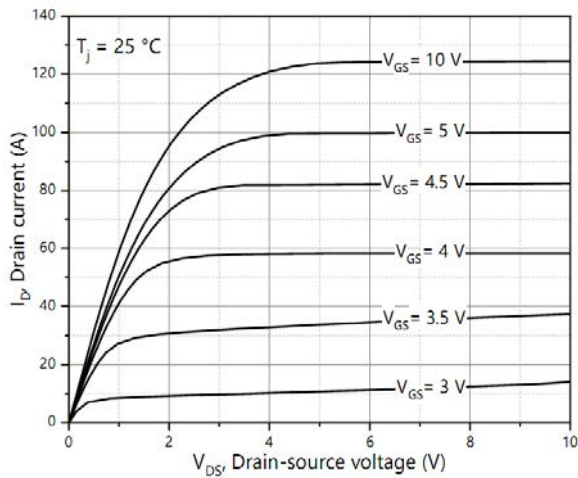


Figure 1. Typ. output characteristics

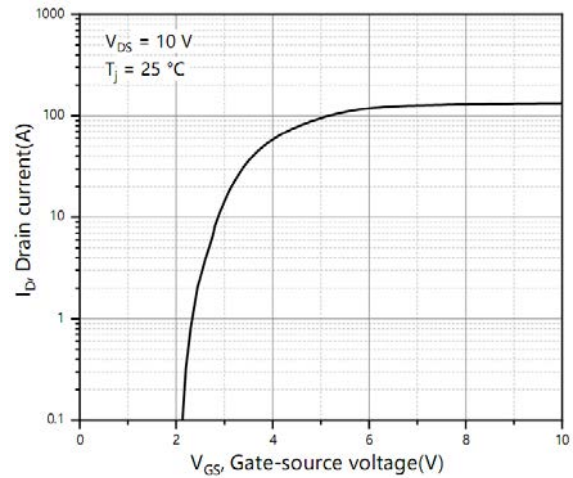


Figure 2. Typ. transfer characteristics

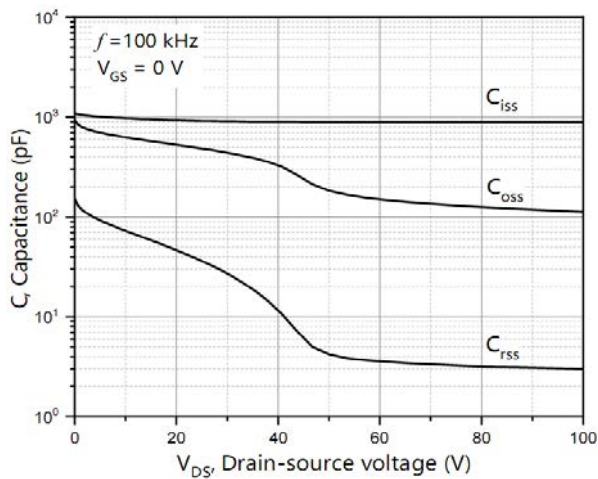


Figure 3. Typ. capacitances

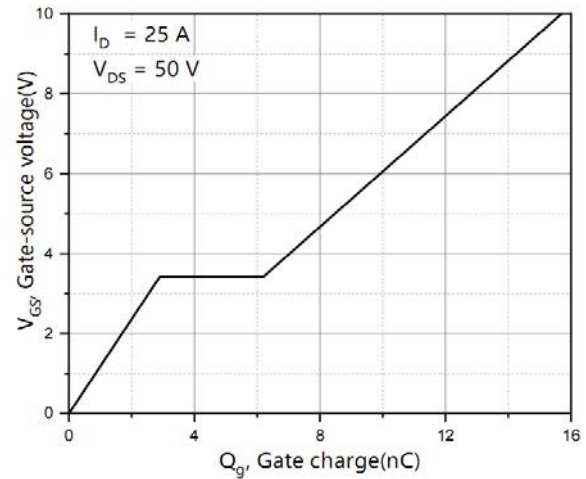


Figure 4. Typ. gate charge

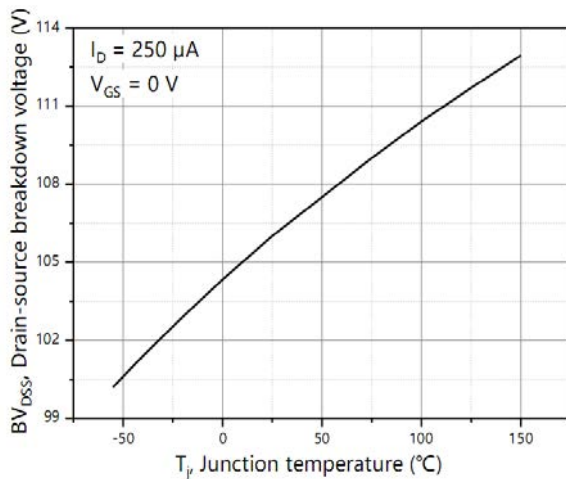


Figure 5. Drain-source breakdown voltage

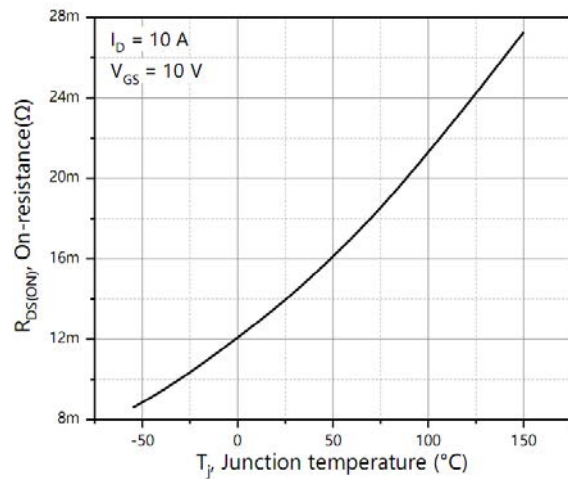


Figure 6. Drain-source on-state resistance

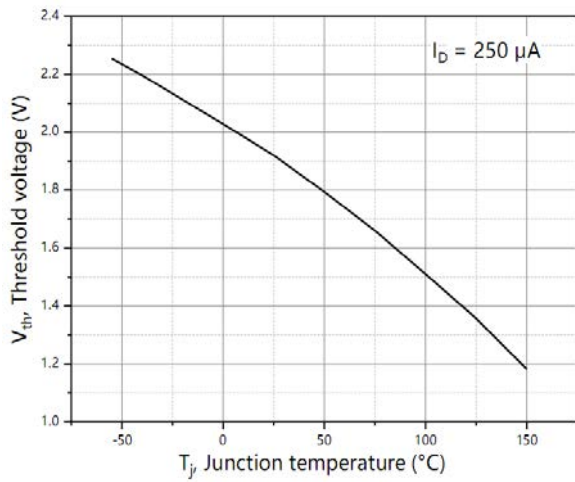


Figure 7. Threshold voltage

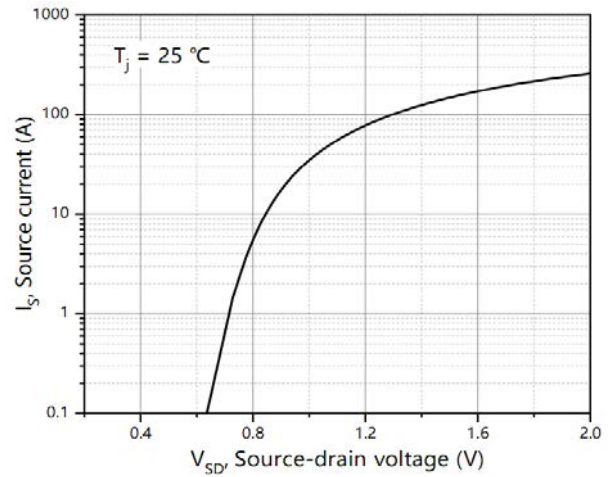


Figure 8. Forward characteristic of body diode

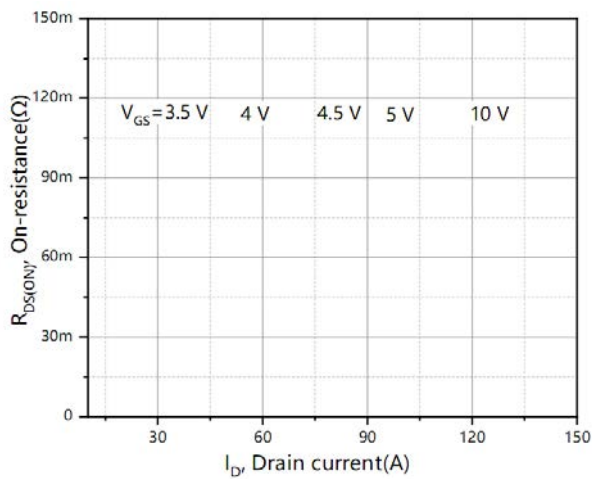


Figure 9. Drain-source on-state resistance

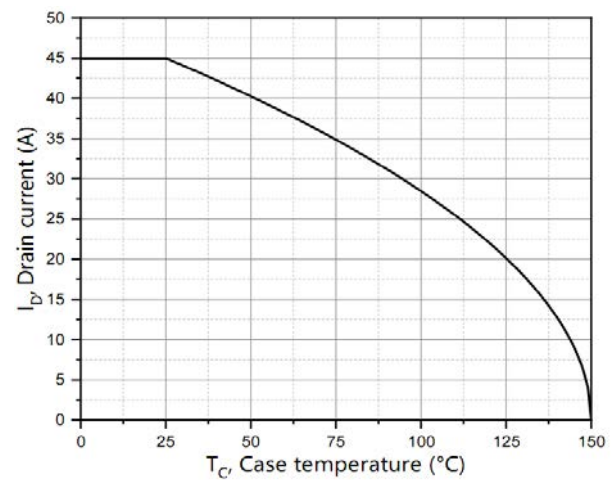


Figure 10. Drain current

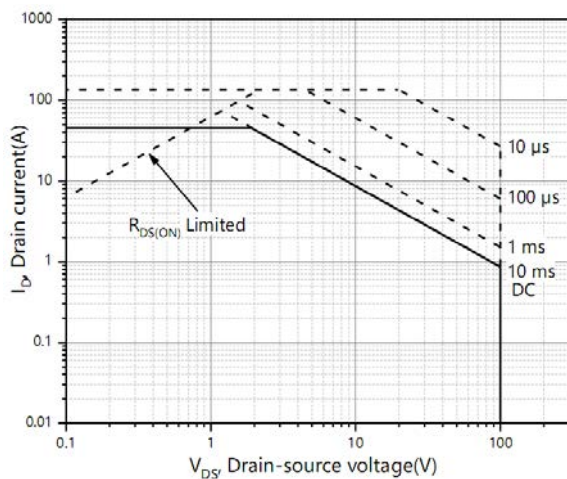


Figure 11. Safe operation area $T_C=25\text{ }^{\circ}\text{C}$

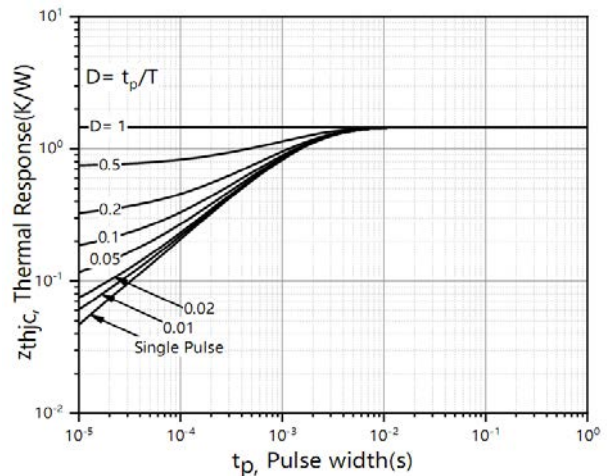
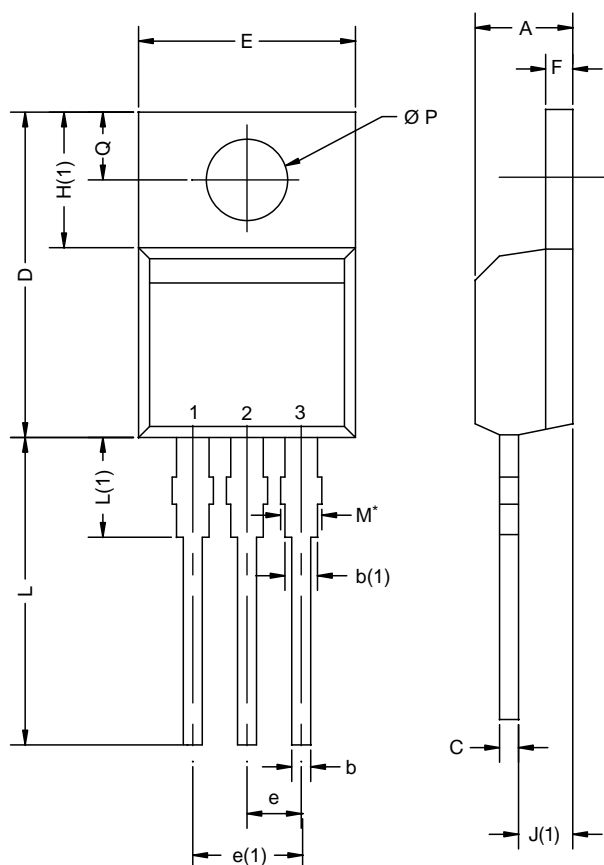


Figure 12. Max. transient thermal impedance



TO-220 Package Information



DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
c	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
Ø P	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118

ECN: X12-0208-Rev. N, 08-Oct-12
DWG: 5471

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion)
Heatsink hole for HVM



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